


<b>Search Notes</b>  	<b>Application/Control No.</b>  10569517	<b>Applicant(s)/Patent Under Reexamination</b>  MAYER ET AL.
	<b>Examiner</b>  EVAN H LANGDON	<b>Art Unit</b>  3654

SEARCHED			
Class	Subclass	Date	Examiner
226	95,97.3	8/11/2008	/EL/
242	615.11,615.12,615.21	8/11/2008	/EL/

SEARCH NOTES		
Search Notes	Date	Examiner

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

	/EVAN H LANGDON/ Primary Examiner.Art Unit 3654
--	--